

Search Notes

Application/Control No.

10/786,388

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

STRECK ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	746	1/11/2007	BT
438	747	1/11/2007	BT
438	756	1/11/2007	BT
438	770	1/11/2007	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438	746	1/11/2007	BT
438	747	1/11/2007	BT
438	756	1/11/2007	BT
438/770		1/11/2007	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT, IBM_TDB databases	1/11/2007	BT